IN THE CLAIMS

Please amend the claims as follows:

- 1. 14. (Cancelled)
- 15. (Original) A method for forming an electrical device comprising:

forming via between a first layer of conductive material and a second layer of conductive material;

lining the via with a conductive material; connecting the lining to a first conductive layer; forming a conductor through the via; connecting the conductor to the first conductive layer; connecting the lining to the second conductive layer; and insulating the lining in the via from the conductor in the via.

- 16. (Original) The method of claim 15 wherein lining the opening with material includes etching the bottom of the opening.
- 17. (Original) The method of claim15 wherein lining the opening with a material includes lining the opening with a magnetizable material.
- 18. (Original) The method of claim 15 wherein lining the opening includes lining the opening with conductive material.
- 19. (Original) A method for forming a device within a via comprising: forming a via;

depositing a first layer of conductive material on inside surface of the via; removing a portion of the deposited first layer of conductive material;

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depositing a dielectric material onto the remaining portion of the conductive material and onto the inner surface of the via;

removing a second portion of the dielectric material; and depositing a second layer of conductive material.

- 20. (Original) The method of claim 19 wherein removing a portion of the deposited first layer includes etching.
- 21. (Original) The method of claim 19 wherein removing a portion of the deposited insulative material includes etching.
- 22. (Original) The method of claim 19 wherein the amount of dielectric material provides an insulator between the first conductive layer and the second conductive layer.
- 23. (Original) A method of forming a device in a via of a substrate comprising: forming a via;

depositing a first pad having a portion associated with the via;
depositing a second pad having a portion associated with the via, the first pad
electrically isolated from the second pad;

filling the via with a resistive material.

- 24. (Original) The method of claim 23 wherein depositing the first pad and depositing the second includes placement proximate a single surface of the substrate.
- 25. (Original) The method of claim 23 wherein depositing the first pad includes placement proximate a first surface of the substrate and depositing the second includes placement proximate a second surface of the substrate.

26. (Original) The method of claim 23 wherein the filling the via with a resistive material includes selecting the resistivity of the material to select the resistance across the via.

27. (Original) A method comprising:

forming a via in a substrate; and

forming at least a portion of an electrical component in the via in the substrate.

28. (Original) The method of claim 27 wherein forming at least a portion of an electrical component in the via includes forming a resistor.

29. (Original) The method of claim 27 wherein forming at least a portion of an electrical component in the via includes forming a capacitor.

30. (Original) The method of claim 27 wherein forming at least a portion of an electrical component in the via includes forming a core.

31. (Original) The method of claim 27 wherein forming at least a portion of an electrical component in the via includes forming at least a portion of a transformer.

32. (New) A method comprising:

forming a via in a substrate; and

forming an electrical component in the via in the substrate.

33. (New) The method of claim 32 wherein forming an electrical component in the via includes forming at least a portion of a resistor.

34. (New) The method of claim 32 wherein forming an electrical component in the via includes forming at least a portion of a capacitor.

- 35. (New) The method of claim 32 wherein forming an electrical component in the via includes forming at least a portion of a core.
- 36. (New) The method of claim 32 wherein forming an electrical component in the via includes forming a resistor.
- 37. (New) The method of claim 32 wherein forming an electrical component in the via includes forming a core.
- 38. (New) The method of claim 32 wherein forming an electrical component in the via includes forming at least a portion of a memory device.
- 39. (New) The method of claim 32 wherein forming an electrical component in the via includes forming a memory device.
- 40. (New) The method of claim 32 wherein the electrical component in the via includes a passive electrical component.
- 41. (New) The method of claim 32 wherein the electrical component in the via is a passive electrical component.
- 42. (New) The method of claim 32 wherein the electrical component is a capacitor further comprising:

an inner cylindrical portion; and an outer via portion substantially surrounding the inner cylindrical portion.

- 43. (New) The method of claim 32 wherein the electrical component is a capacitor further comprising:
 - a first curved portion; and

a second curved portion spaced from the first curved portion, wherein the distance between the first curved portion and the second curved portion vary.

- 44. (New) The method of claim 32 wherein the electrical component is a capacitor further comprising:
 - a first curved portion; and
- a second curved portion spaced from the first curved portion, wherein the first curved portion and the second curved portion are portions of a via formed by insulating a first portion of a via from a second portion of a via..
- 45. (New) The method of claim 32 wherein forming an electrical component in the via includes forming at least a portion of a transformer.